



FORM PTO-1449/A and B (Modified) INFORMATION DISCLOSURE STATEMENT BY APPLICANT		APPLICATION NO.: 09/813,454	ATTY. DOCKET NO.: A0770/7037
		FILING DATE: March 20, 2001	
		APPLICANT: Sigurd Wagner et al.	
		GROUP ART UNIT: 2877 2826	EXAMINER: Unassigned Minhloan Tran
Sheet	1	of	1

U.S. PATENT DOCUMENTS

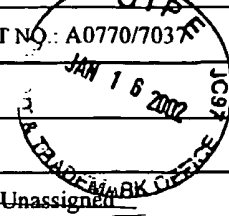
Examiner's Initials#	Cite No.	U.S. Patent Document		Name of Patentee or Applicant of Cited Document	Date of Publication or of issue of Cited Document MM-DD-YYYY
		Number	Kind Code		
MLT	A1	5,185,272	B1	Makiuchi et al.	02-09-1993
MLT	A2	5,528,071	B1	Russell et al.	06-18-1996
MLT	A3	5,599,403	B1	Kariya et al.	02-04-1997
MLT	A4	5,767,712	B1	Takemae et al.	06-16-1998
MLT	A5	5,790,255	B1	Jackson et al.	08-04-1998

FOREIGN PATENT DOCUMENTS

Examiner's Initials#	Cite No.	Foreign Patent Document			Name of Patentee or Applicant of Cited Document (not necessary)	Date of Publication of Cited Document MM-DD-YYYY	Translation (Y/N)
		Office/Country	Number	Kind Code			
MLT	B1	EP	0 125 390	A1	SCHAUMBERG HANNO	11-21-1984	N
	B2	EP	0 559 347	A1	AMERICAN TELEPHONE AND TELEGRAPH COMPANY	09-08-1993	
	B3	JP	08 250551	A	MITSUBISHI ELECTRIC CORP.	09-27-1996	Abstract
	B4	EP	0 883 194	A1	UNIV ROMA	12-09-1998	
MLT	B5	WO	01/73850	A2	AEGIS SEMICONDUCTOR	10-04-2001	

EXAMINER Minhloan Tran	DATE CONSIDERED 1/04
---------------------------	-------------------------

#EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

FORM PTO-1449/A and B (Modified) INFORMATION DISCLOSURE STATEMENT BY APPLICANT				APPLICATION NO.: 09/813,454	
				FILING DATE: March 20, 2001	
				APPLICANT: Sigurd Wagner et al.	
				GROUP ART UNIT: 2877 2826	EXAMINER: Unassigned Minhloan Tran
Sheet	1	of	1		

U.S. PATENT DOCUMENTS

Examiner's Initials#	Cite No.	U.S. Patent Document		Name of Patentee or Applicant of Cited Document	Date of Publication or of issue of Cited Document MM-DD-YYYY
		Number	Kind Code		
MLT	A1	4,885,622	B1	Uchiyama et al.	12-05-1989
	A2	5,162,239	B1	Winer et al.	11-10-1992
	A3	5,539,848	B1	Galloway	07-23-1996
	A4	5,742,630	B1	Jiang et al.	04-21-1998
	A5	5,751,757	B1	Jiang et al.	05-12-1998
	A6	5,942,050	B1	Green et al.	08-24-1999
	A7	5,953,355	B1	Kiely et al.	09-14-1999
MLT	A8	6,037,644	B1	Daghighian et al.	03-14-2000

FOREIGN PATENT DOCUMENTS

Examiner's Initials#	Cite No.	Foreign Patent Document			Name of Patentee or Applicant of Cited Document (not necessary)	Date of Publication of Cited Document MM-DD-YYYY	Translation (Y/N)
		Office/Country	Number	Kind Code			
MLT	B1	EP	0 139 487	A1	EXXON RES. AND ENG. CO.	05-02-1985	
	B2	JP	60 210826	A	MITSUBISHI ELECTRIC CORP.	10-23-1985	Abstract
	B3	EP	0 178 148	A2	XEROX CORPORATION	04-16-1986	
	B4	WO	89/03593	A1	STEMCOR CORPORATION	04-20-1989	
	B5	JP	07 168040	A	NIPPON STEEL CORP.	07-04-1995	Abstract
	B6	EP	0 860 885	A2	CANON KABUSHIKI KAISHA	08-26-1998	
	B7	EP	0 899 835	A1	XEROX CORP.	03-03-1999	
	B8	EP	0 899 836	A1	XEROX CORP.	03-03-1999	
MLT	B9	WO	99/30394	A	COHERENT, INC.	06-17-1999	

OTHER ART — NON PATENT LITERATURE DOCUMENTS

Examiner's Initials#	Cite No	Include name of the author (in CAPITAL LETTERS) title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, relevant page(s), volume-issue number(s), publisher, city and/or country where published.	Translation (Y/N)	
MLT	C1	Fernandes M et al., "VIS/NIR detector based on μ -Si:H p-i-n structures", Thin Solid Films, Elsevier Science S.A., Lausanne, CH, vol. 364, no. 1-2, March 2000, pp. 204-208.		
MLT	C2	Kobayashi Y et al., "Improvement on Coupling Efficiency for Passive Alignment of Stacked Multi-Fiber Tapes to a Vertical-Cavity Surface-Emitting Laser Array", Extended Abstracts of the 1996 International Conference on Solid State Devices and Materials, Yokohama, Japan, 1996, pp. 655-657, XP 000694099		
MLT	C3	Wipiejewski T et al., "Vertical-Cavity Surface-Emitting Laser Diodes for Short Distance Optical Fiber Networks", Proceeding of the Electronic Components and Technology Conference, Washington, D.C., May 1-4, 1994, New York, IEEE, US, Vol. 44, May 1, 1994, pp 330-334, XP 000479165		

EXAMINER Minhloan Tran	DATE CONSIDERED 1/04
---------------------------	-------------------------

#EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.